ICOMP International Conference on COmputational methods in Manufacturing Processes

Comparison of interval and stochastic methods for uncertainty quantification in metal forming

M. Arnst, K. Liegeois, R. Boman, and J.-P. Ponthot

May 18, 2016

# **Motivation**



# This presentation compares interval and stochastic methods for studying the impact of manufacturing variability in series production in sheet metal forming.

## Outline

Motivation.

Outline.

Interval and stochastic methods.

Application to sheet metal forming.

Conclusion.

Interval and stochastic methods

# **Problem setting**

Raw materials variability:

• Material properties.

Process variability:

- Blank holder force.
- Initial dimensions.
- Friction.

. . .

. . .

. . .

### Modeling limitations:

- Constitutive model.
- FE discretization.



 $\rightarrow$ 

Product variability:

- Final dimensions.
- Springback.

. . .

. . .

Prediction limitations:

• Numerical noise.

### Input variables

 $(x_1, x_2, \ldots, x_m)$ 

 $\begin{array}{c} \textbf{Mapping} \\ y = g(x_1, x_2, \dots, x_m) \end{array}$ 

### Output variable

y

## **Overview**



The computational cost of both interval and stochastic methods can be lowered via the use of a surrogate model as a substitute for a FE model or the real process.

### Characterization of variability:

Available information Catalogue bounds Production data

. . .

Intervals  $[\underline{x}_1, \overline{x}_1], \dots, [\underline{x}_m, \overline{x}_m]$ 

### Propagation of variability:

 $\begin{bmatrix} \underline{x}_1, \overline{x}_1 \end{bmatrix}, \dots, \begin{bmatrix} \underline{x}_m, \overline{x}_m \end{bmatrix} \xrightarrow{\text{optimization}} \begin{bmatrix} \text{Interval} \\ [y, \overline{y}] \end{bmatrix}$ 

$$\underline{y} = \min_{\underline{x}_1 \le x_1 \le \overline{x}_1} g(x_1, \dots, x_m) \text{ and } \overline{y} = \max_{\underline{x}_1 \le x_1 \le \overline{x}_1} g(x_1, \dots, x_m).$$

$$\vdots$$

$$\underline{x}_m \le x_m \le \overline{x}_m$$

$$\vdots$$

$$\underline{x}_m \le \overline{x}_m$$

#### Sensitivity analysis:

• Local sensitivity descriptors, such as  $\frac{\partial y}{\partial x_1}$ ,  $\frac{\partial y}{\partial \overline{x}_1}$ , ...,  $\frac{\partial \overline{y}}{\partial \overline{x}_m}$ ,  $\frac{\partial \overline{y}}{\partial \overline{x}_m}$ , and their variants.



Generate an ensemble of samples of  $x_1, \ldots, x_m$  following probability density function  $\rho_{(x_1, \ldots, x_m)}$ . Map each sample of  $x_1, \ldots, x_m$  into the corresponding sample of y. Deduce probability density function  $\rho_y$  and other statistical descriptors of y.

### Sensitivity analysis:

- Local sensitivity descriptors, such as  $\frac{\partial y}{\partial x_1}, \ldots, \frac{\partial y}{\partial x_m}$ , and their variants.
- Global sensitivity descriptors that indicate the significance of the variability in each input.



$$\approx$$

$$y = \sum_{(\alpha_1, \dots, \alpha_m)} c_{(\alpha_1, \dots, \alpha_m)} x_1^{\alpha_1} \times \dots \times x_m^{\alpha_m}$$

Real process or FE model.



Training set  $y^{(1)} = g(x_1^{(1)}, \dots, x_m^{(1)})$   $\vdots$   $y^{(n)} = g(x_1^{(n)}, \dots, x_m^{(n)})$ Surrogate model  $y = \sum c_{(\alpha_1, \dots, \alpha_m)} x_1^{\alpha_1} \times \dots \times x_m^{\alpha_m}$ 

The computational cost of interval and stochastic methods can be lowered via the use of a surrogate model as a substitute for the real process or a FE model.

Application to sheet metal forming

# **Problem setting**

We consider an "omega" sheet metal forming process:



We assume that manufacturing variability manifests itself as variability in the ultimate tensile stress  $R_m$  and the strain hardening coefficient n, and we are interested in the impact of this manufacturing variability on a geometrical characteristic of the springback, which we denote by y:



We assume that the following information is available:



FE model.

j [-]	$R_{\sf m}$ [MPa]	$n\left[- ight]$
1	659	0.164
	•	:
25	646	0.162

Production data (fictitious).

 $600 \,\mathrm{MPa} \leq R_{\mathrm{m}} \leq 700 \,\mathrm{MPa}$  $0.14 \leq n \leq 0.22$ 

### Catalogue bounds (DP600).

ICOMP, Liège, Belgium

In order to lower the computational cost, we construct a surrogate model to serve as a substitute for the FE model in the interval and stochastic analyses:



We construct the surrogate model by using the FE model to evaluate for a small number of well chosen values of  $R_m$  and n corresponding values of y and then applying a regression method:



### **Interval methods**

#### Characterization of variability



### **Interval methods**

### Propagation of variability



$$7.93\,\mathrm{mm} = \min_{\substack{600 \le R_{\mathrm{m}} \le 700\\0.14 \le n \le 0.22}} g(R_{\mathrm{m}}, n) \quad \text{and} \quad 11.59\,\mathrm{mm} = \max_{\substack{600 \le R_{\mathrm{m}} \le 700\\0.14 \le n \le 0.22}} g(R_{\mathrm{m}}, n).$$

## **Stochastic methods**

#### Characterization of variability





We generated an ensemble of samples of  $R_m$  and n following their probability density function, mapped each sample of  $R_m$  and n into a corresponding value of y, and applied mathematical statistics method to deduce the probability density function and other statistical descriptors of y:



# **Stochastic methods**

#### Sensitivity analysis

In addition to a local sensitivity analysis, for which we do not show results here, stochastic methods allow a global sensitivity analysis, which can indicate the significance of the variability in each input:



A global sensitivity analysis based on the analysis-of-variance method, about which we do not provide details here, indicates that the variability in  $R_m$  is most significant in inducing variability in y.

# **Stochastic methods**

Interval and stochastic methods involve different representations of variability:

- Intervals describe ranges of values.
- Probability density functions functions describe frequencies of occurrence.

Interval and stochastic methods require different types of information to be available:

- Interval methods require that the available information allows the ranges of values of the variable properties of the manufacturing process to be bounded.
- Stochastic methods require that the available information allows the frequencies of occurrence of the variable properties of the manufacturing process to be modeled.
- Interval and stochastic methods provide different types of insight:
  - Interval methods describe the impact of the manufacturing variability in terms of ranges of values for properties of the formed object.
  - Stochastic methods describe the impact of the manufacturing variability in terms of frequencies of occurrence of properties of the formed object..
- The computational cost of both interval and stochastic methods can be lowered via the use of a surrogate model as a substitute for a FE model or the real process.

# **References and acknowledgements**

L. Papeleux and J.-P. Ponthot. Finite element simulation of springback in sheet metal forming. Journal of Materials Processing Technology, 125–126:785–791, 2002.

M. Arnst and J.-P. Ponthot. An overview of nonintrusive characterization, propagation, and sensitivity analysis of uncertainties in computational mechanics. International Journal for Uncertainty Quantification, 4:387–421, 2014.

M. Arnst, B. Abello Alvarez, J.-P. Ponthot, and R. Boman. Itô-SDE-based MCMC method for Bayesian characterization and propagation of errors associated with data limitations. SIAM/ASA Journal on Uncertainty Quantification, Submitted, 2016.

Support of ArcelorMittal and support of the University of Liège through a starting grant are gratefully acknowledged.